

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10653791	OHBA, AKIO
	<b>Examiner</b> Repko, Jason M	<b>Art Unit</b> 2628

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST text search (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB -- see search history printout)	11/7/2006	JMR
Consulted Examiners in QEM 2628: Kimbinh Nguyen, Dan Hajnik, Andrew Yang, Crystal Murdoch	11/9/2006	JMR
EAST text search (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB -- see search history printout)	5/18/2007	JMR
Google search (see search history printout)	5/18/2007	JMR
345/418-428, 345/473-475, and 345/629 (text search only see search history printout)	5/18/2007	JMR
Consulted Examiners in QEM 2628: Kimbinh Nguyen, Andrew Yang, Peter Pappas, Crystal Murdoch	5/17/2007	JMR
Inventor Name search	7/31/2007	JMR

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
345	418-428, 473-475, 629	5/18/2007	JMR
345	418-428, 473-475, 629	7/31/2007	JMR